

N-Channel Enhancement Mode Power MOSFET

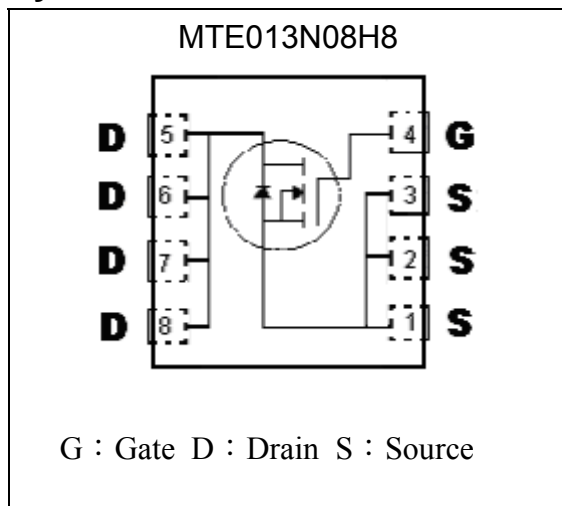
MTE013N08H8

BV_{DSS}	80V
I_D@V_{GS}=10V, T_C=25°C	40A
I_D@V_{GS}=10V, T_A=25°C	10.5A
R_{DS(ON)}@V_{GS}=10V, I_D=10A	9.1 mΩ (typ)

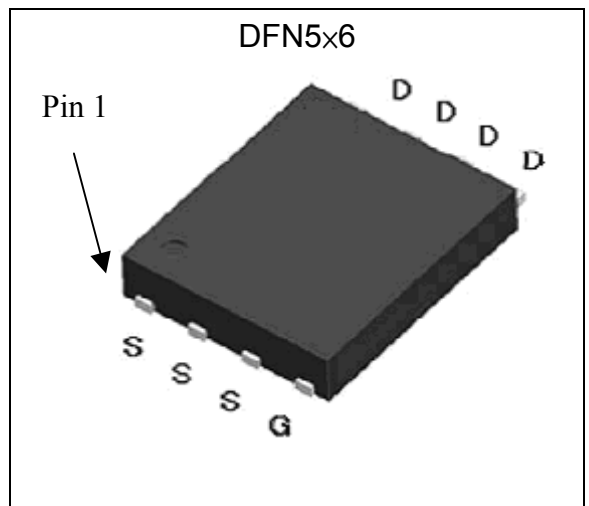
Features

- Low On Resistance
- Simple Drive Requirement
- Low Gate Charge
- Fast Switching Characteristic
- Pb-free lead plating and halogen-free package

Symbol

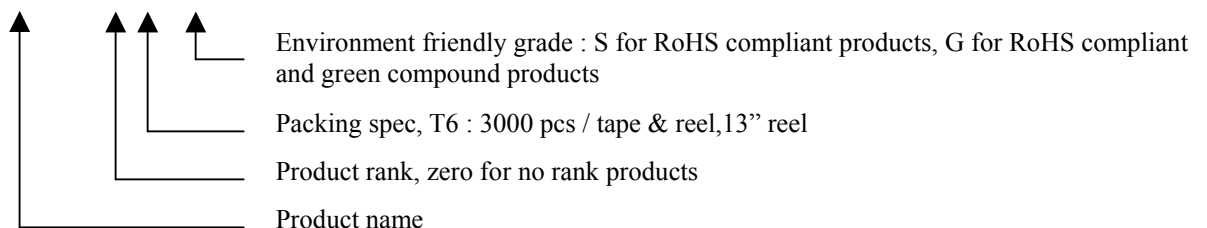


Outline



Ordering Information

Device	Package	Shipping
MTE013N08H8-0-T6-G	DFN5x6 (Pb-free lead plating and halogen-free package)	3000 pcs / Tape & Reel



**Absolute Maximum Ratings** ($T_C=25^{\circ}\text{C}$)

Parameter	Symbol	Limits	Unit
Drain-Source Voltage (Note 1)	V_{DS}	80	V
Gate-Source Voltage	V_{GS}	± 20	
Continuous Drain Current @ $T_C=25^{\circ}\text{C}$, $V_{GS}=10\text{V}$ (silicon limit) (Note 4)	I_D	57	A
Continuous Drain Current @ $T_C=25^{\circ}\text{C}$, $V_{GS}=10\text{V}$ (package limit) (Note 4)		40	
Continuous Drain Current @ $T_C=100^{\circ}\text{C}$, $V_{GS}=10\text{V}$		36	
Continuous Drain Current @ $T_A=25^{\circ}\text{C}$, $V_{GS}=10\text{V}$ (Note 2)	I_{DSM}	10.5	
Continuous Drain Current @ $T_A=70^{\circ}\text{C}$, $V_{GS}=10\text{V}$ (Note 2)		8.4	
Pulsed Drain Current (Note 1)	I_{DM}	160	
Single Pulse Avalanche Current @ $L=0.1\text{mH}$	I_{AS}	40	
Single Pulse Avalanche Energy @ $L=5\text{mH}$, $I_D=20\text{Amps}$, $V_{DD}=30\text{V}$ (Note 3)	E_{AS}	1000	mJ
Repetitive Avalanche Energy	E_{AR}	6.9	
Power Dissipation	P_D	$T_C=25^{\circ}\text{C}$	69
		$T_C=100^{\circ}\text{C}$	27
	P_{DSM}	$T_A=25^{\circ}\text{C}$ (Note 2)	2.5
		$T_A=70^{\circ}\text{C}$ (Note 2)	1.6
Operating Junction and Storage Temperature	T_j, T_{stg}	-55~+150	

*Drain current limited by maximum junction temperature

Thermal Data

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-case, max	$R_{\theta JC}$	1.8	$^{\circ}\text{C}/\text{W}$
Thermal Resistance, Junction-to-ambient, max (Note 2)	$R_{\theta JA}$	50	

- Note :
1. Pulse width limited by junction temperature.
 2. Surface mounted on 1 in² copper pad of FR-4 board, 125 $^{\circ}\text{C}/\text{W}$ when mounted on minimum copper pad
 3. Ratings are based on low frequency and low duty cycles to keep initial $T_j=25^{\circ}\text{C}$. 100% tested by conditions of $V_{DD}=30\text{V}$, $I_D=20\text{A}$, $L=0.1\text{mH}$, $V_{GS}=10\text{V}$.
 4. Calculated continuous drain current based on maximum allowable junction temperature.
 5. The static characteristics are obtained using <300 μs pulses, duty cycle 0.5% maximum.
 6. The $R_{\theta JA}$ is the sum of thermal resistance from junction to case $R_{\theta JC}$ and case to ambient.

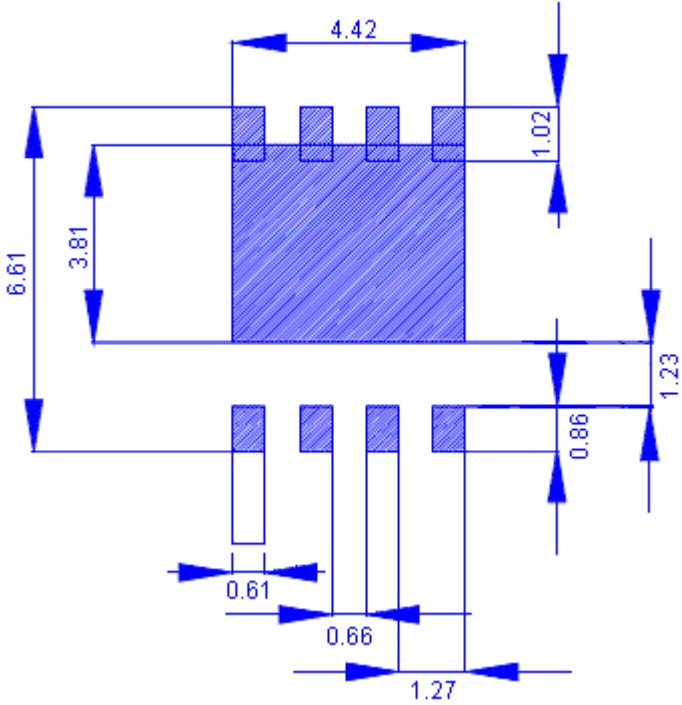


Characteristics (Tj=25°C, unless otherwise specified)

Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Static					
BV _{DSS}	80	-	-	V	V _{GS} =0V, I _D =250μA
ΔBV _{DSS} /ΔT _j	-	68	-	mV/°C	Reference to 25°C, I _D =250μA
V _{GS(th)}	2	-	4	V	V _{DS} = V _{GS} , I _D =250μA
*G _{FS}	-	19	-	S	V _{DS} =10V, I _D =20A
I _{GSS}	-	-	±100	nA	V _{GS} =±20V
I _{DSS}	-	-	1	μA	V _{DS} =64V, V _{GS} =0V
	-	-	5		V _{DS} =64V, V _{GS} =0V, T _j =55°C
*R _{DS(ON)}	-	9.1	11.5	mΩ	V _{GS} =10V, I _D =10A
Dynamic					
*Q _g (V _{GS} =10V)	-	31.4	-	nC	V _{DS} =40V, V _{GS} =10V, I _D =10.5A
*Q _g (V _{GS} =8V)	-	26	-		
*Q _{gs}	-	7.3	-		
*Q _{gd}	-	10.1	-		
*t _{d(ON)}	-	18.6	-	ns	V _{DS} =40V, I _D =10.5A, V _{GS} =10V, R _{GS} =6Ω
*tr	-	26.2	-		
*t _{d(OFF)}	-	46	-		
*tr	-	15.8	-		
C _{iss}	-	1472	-	pF	V _{GS} =0V, V _{DS} =30V, f=1MHz
C _{oss}	-	200	-		
C _{rss}	-	105	-		
R _g	-	3.8	-		
Source-Drain Diode					
*I _S	-	-	40	A	
*I _{SM}	-	-	160		
*V _{SD}	-	0.74	1.1	V	I _S =2.8A, V _{GS} =0V
*trr	-	24.4	-	ns	V _{GS} =0V, I _F =10.5A, dI _F /dt=100A/μs
*Q _{rr}	-	26.9	-	nC	

*Pulse Test : Pulse Width ≤300μs, Duty Cycle≤2%

Recommended Soldering Footprint

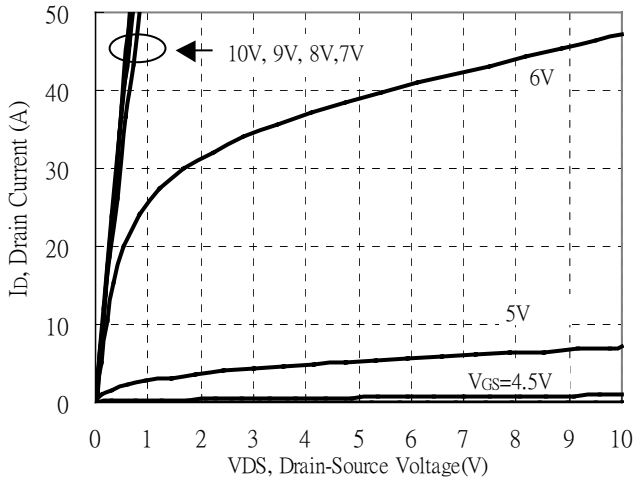


unit : mm

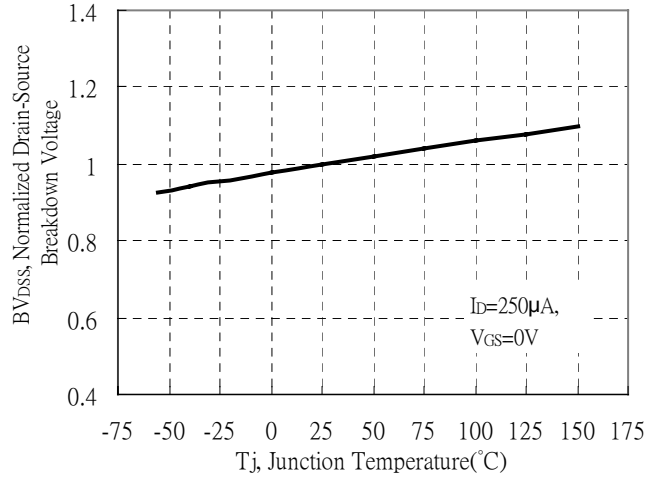


Typical Characteristics

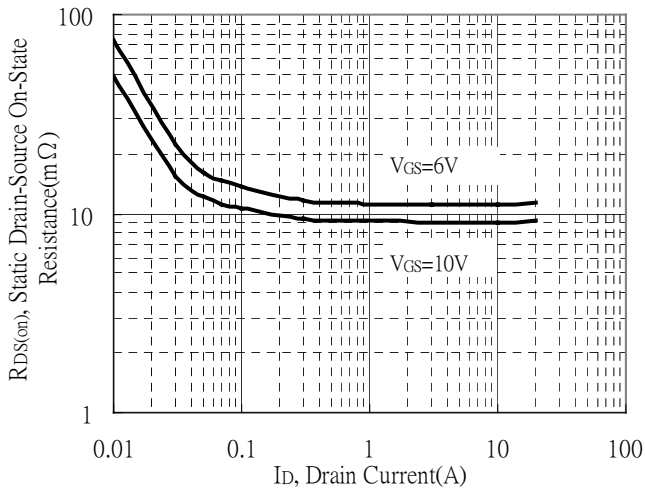
Typical Output Characteristics



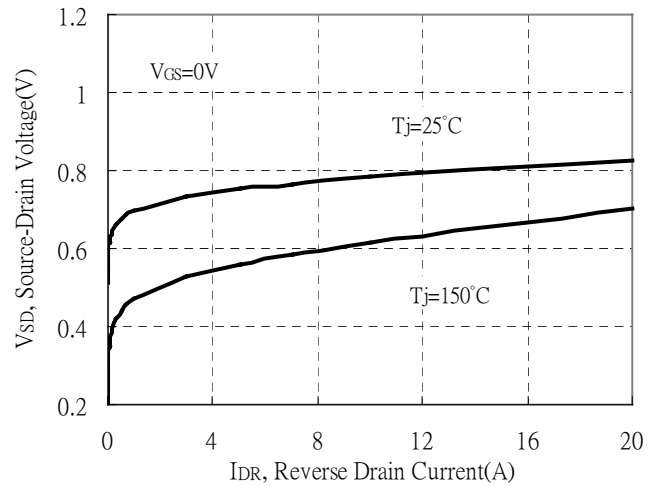
Brekdown Voltage vs Junction Temperature



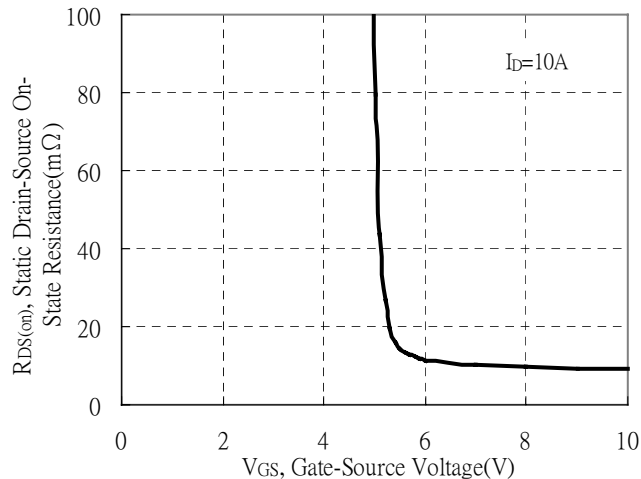
Static Drain-Source On-State resistance vs Drain Current



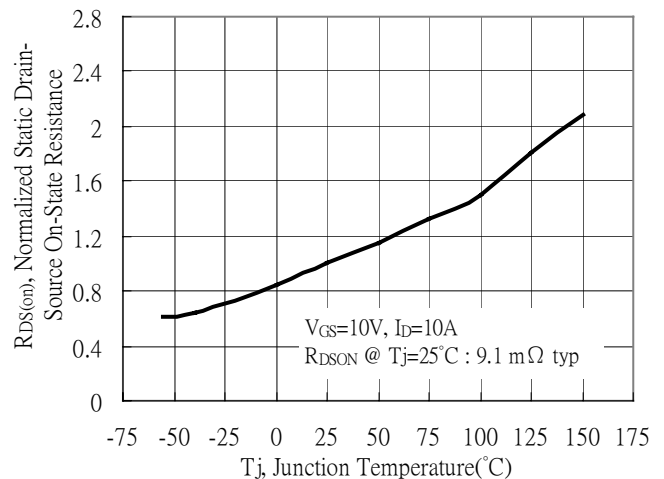
Reverse Drain Current vs Source-Drain Voltage



Static Drain-Source On-State Resistance vs Gate-Source Voltage



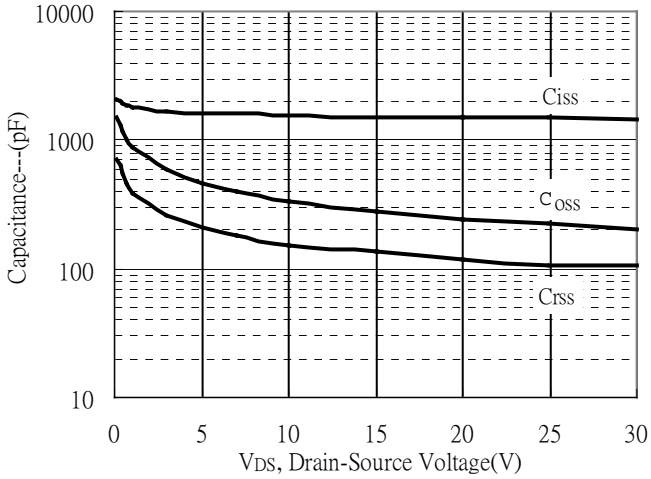
Drain-Source On-State Resistance vs Junction Temperature



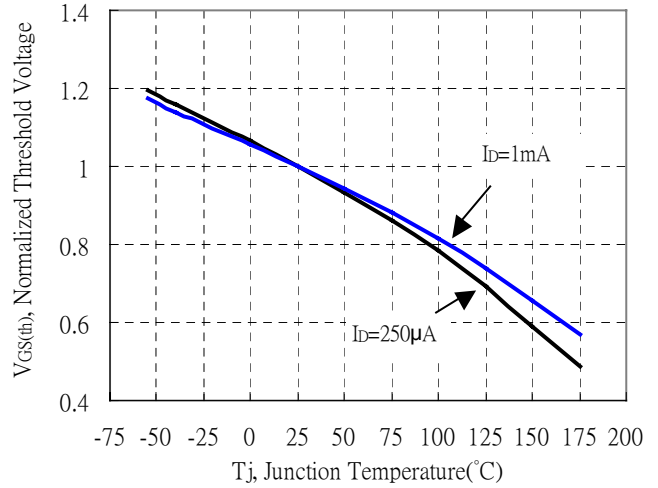


Typical Characteristics(Cont.)

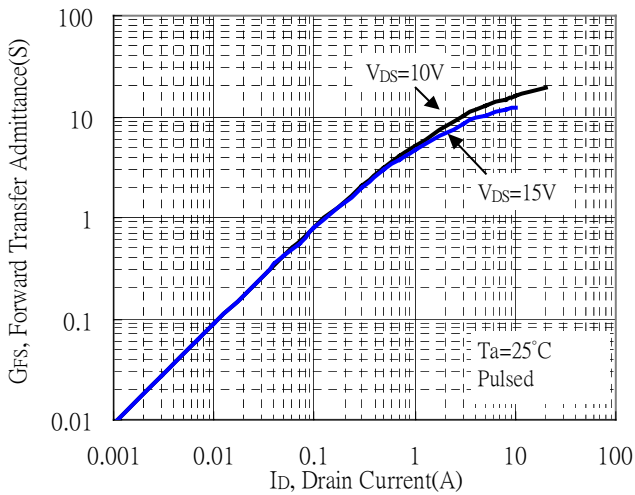
Capacitance vs Drain-to-Source Voltage



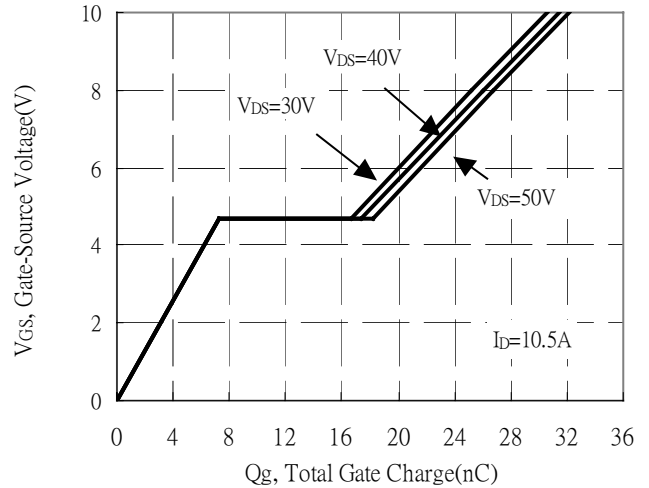
Threshold Voltage vs Junction Temperature



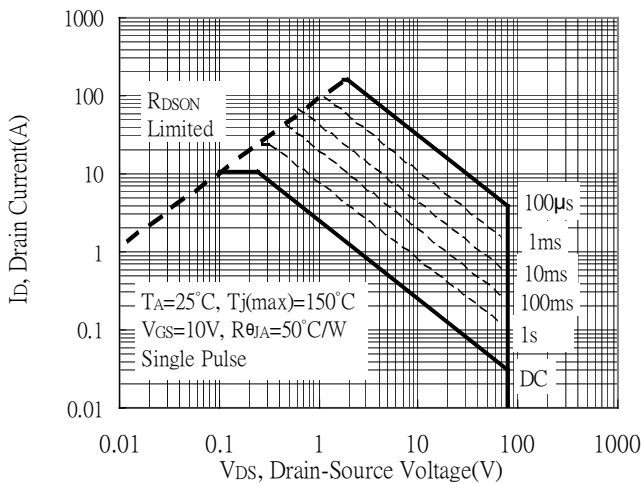
Forward Transfer Admittance vs Drain Current



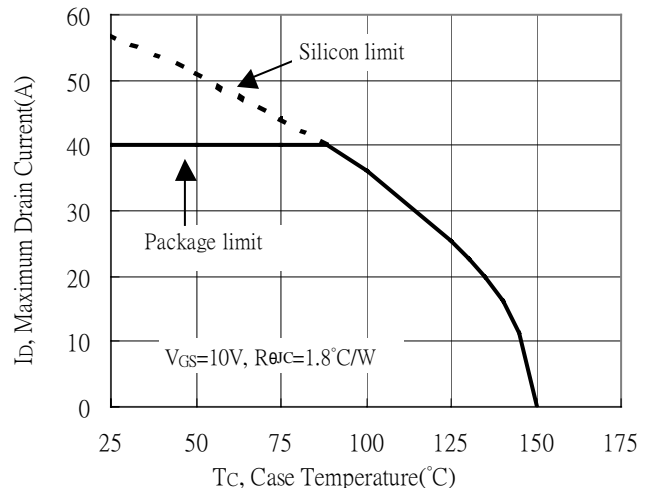
Gate Charge Characteristics



Maximum Safe Operating Area



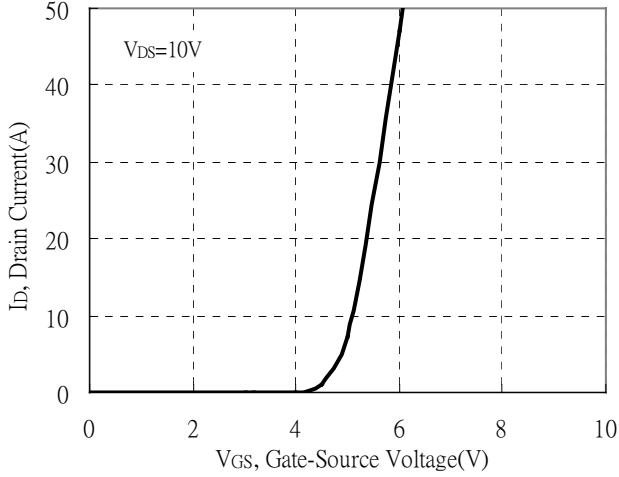
Maximum Drain Current vs Case Temperature



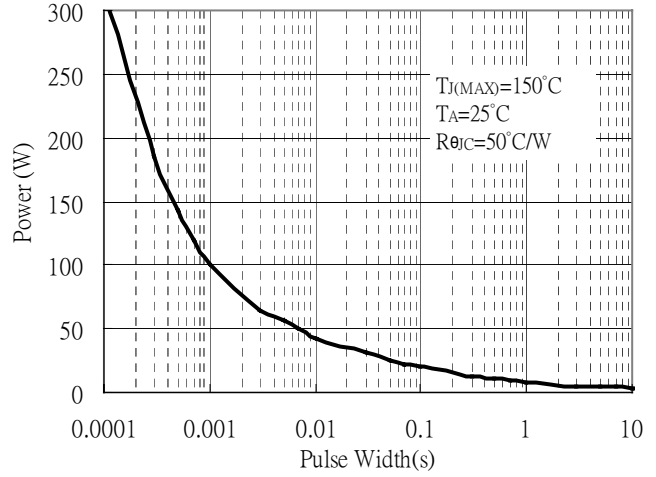


Typical Characteristics(Cont.)

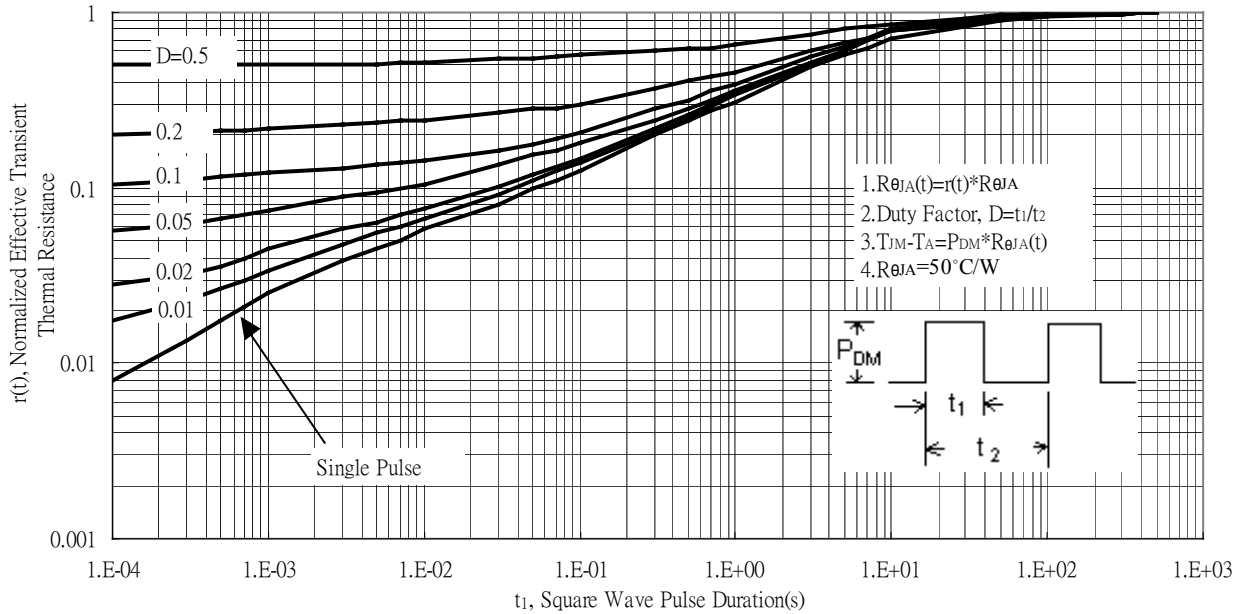
Typical Transfer Characteristics



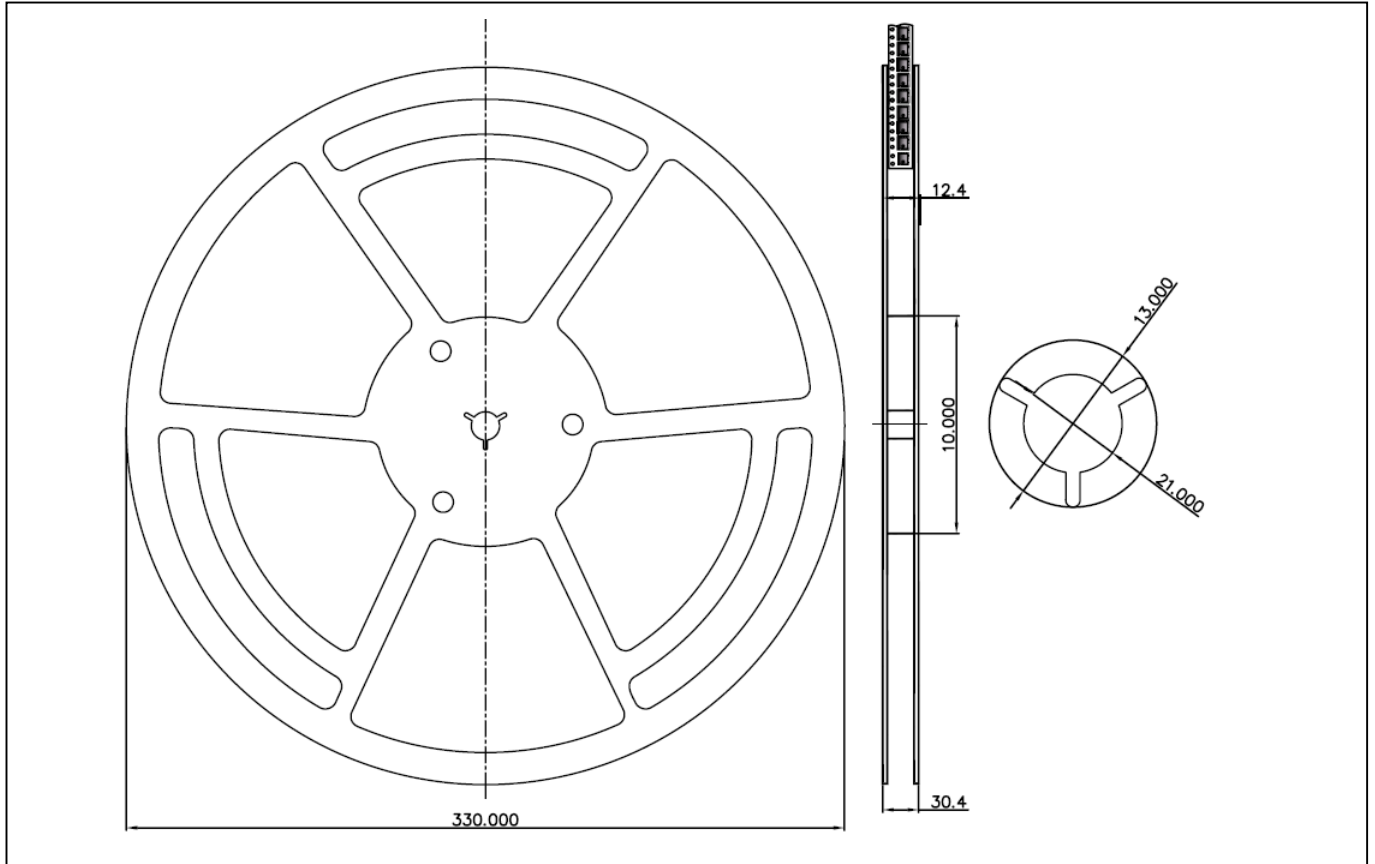
Single Pulse Power Rating, Junction to Case



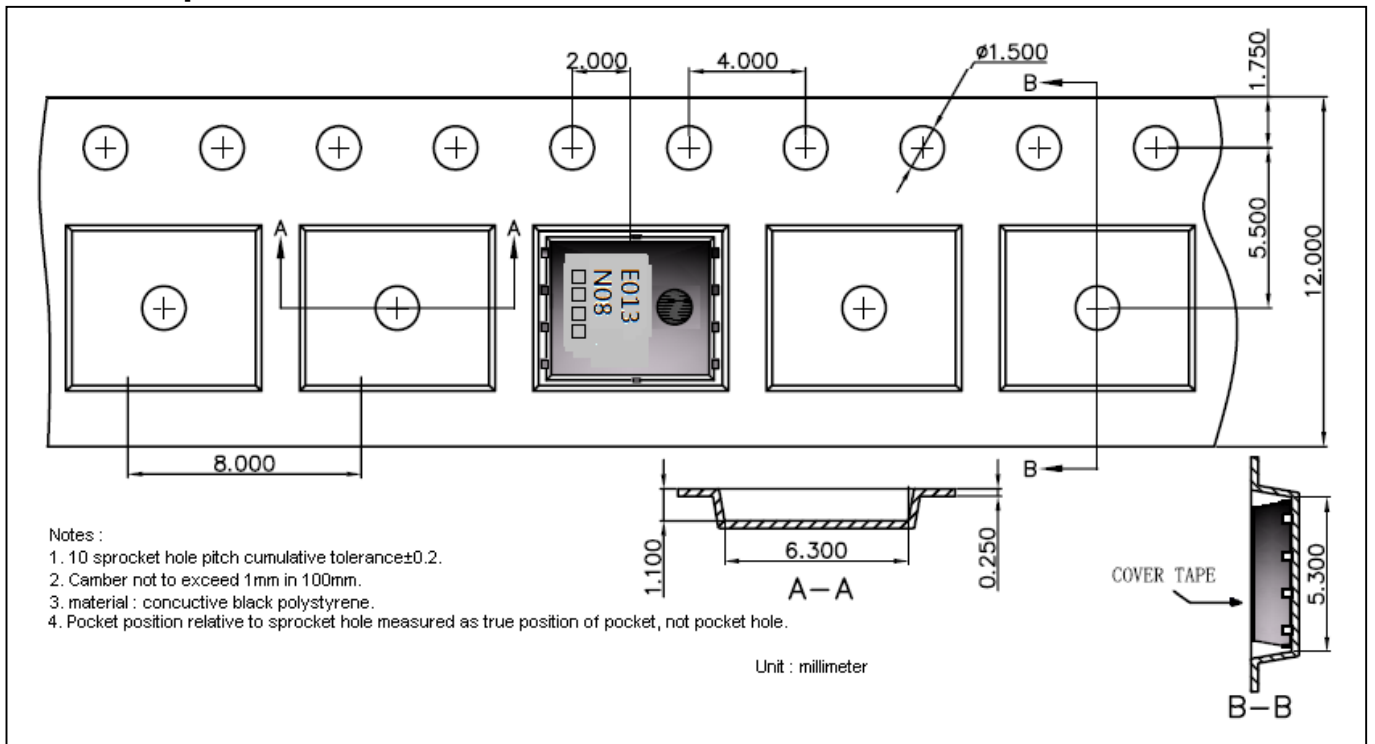
Transient Thermal Response Curves



Reel Dimension



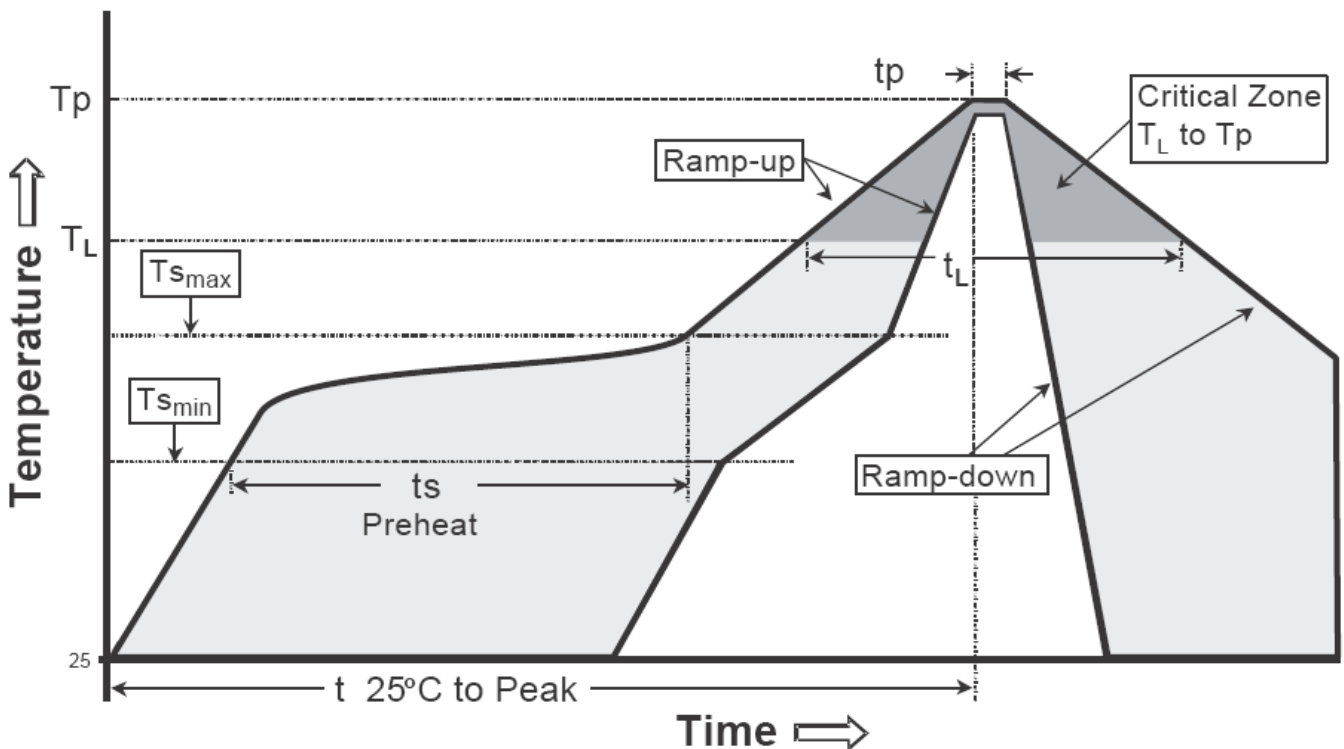
Carrier Tape Dimension



Recommended wave soldering condition

Product	Peak Temperature	Soldering Time
Pb-free devices	260 +0/-5 °C	5 +1/-1 seconds

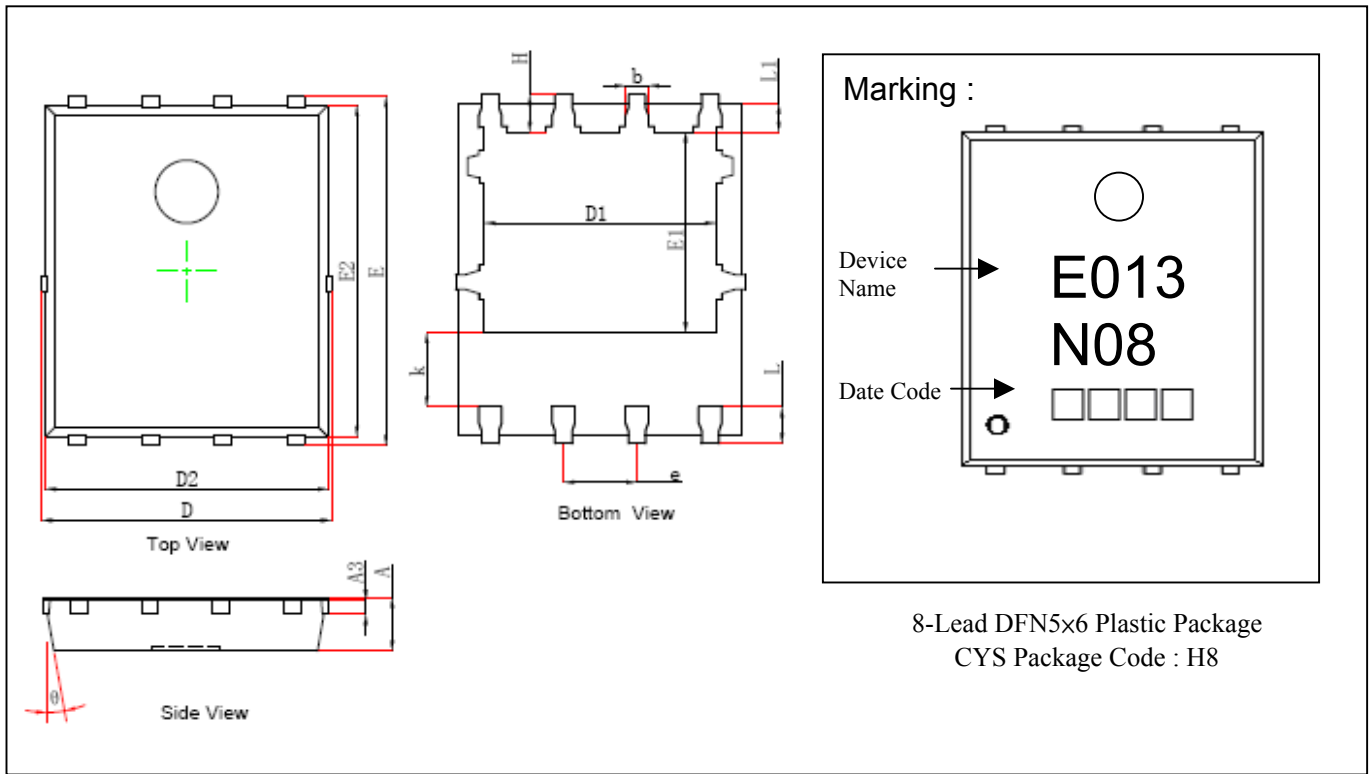
Recommended temperature profile for IR reflow



Profile feature	Sn-Pb eutectic Assembly	Pb-free Assembly
Average ramp-up rate (T _{smax} to T _p)	3°C/second max.	3°C/second max.
Preheat		
-Temperature Min(T _{s min})	100°C	150°C
-Temperature Max(T _{s max})	150°C	200°C
-Time(t _{s min} to t _{s max})	60-120 seconds	60-180 seconds
Time maintained above:		
-Temperature (T _L)	183°C	217°C
- Time (t _L)	60-150 seconds	60-150 seconds
Peak Temperature(T _P)	240 +0/-5 °C	260 +0/-5 °C
Time within 5°C of actual peak temperature(t _p)	10-30 seconds	20-40 seconds
Ramp down rate	6°C/second max.	6°C/second max.
Time 25 °C to peak temperature	6 minutes max.	8 minutes max.

Note : All temperatures refer to topside of the package, measured on the package body surface.

DFN5x6 Dimension



DIM	Millimeters		Inches		DIM	Millimeters		Inches	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
A	0.900	1.000	0.035	0.039	k	1.190	1.390	0.047	0.055
A3	0.254	REF	0.010	REF	b	0.350	0.450	0.014	0.018
D	4.944	5.096	0.195	0.201	e	1.270	TYP.	0.050	TYP.
E	5.974	6.126	0.235	0.241	L	0.559	0.711	0.022	0.028
D1	3.910	4.110	0.154	0.162	L1	0.424	0.576	0.017	0.023
E1	3.375	3.575	0.133	0.141	H	0.574	0.726	0.023	0.029
D2	4.824	4.976	0.190	0.196	θ	10°	12°	10°	12°
E2	5.674	5.826	0.223	0.229					

Notes: 1.Controlling dimension: millimeters.
 2.Maximum lead thickness includes lead finish thickness, and minimum lead thickness is the minimum thickness of base material.
 3.If there is any question with packing specification or packing method, please contact your local CYStek sales office.

Material:

- Lead: Pure tin plated.
- Mold Compound: Epoxy resin family, flammability solid burning class: UL94V-0.

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